Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/717,870	BEYER ET AL.	
Examiner	Art Unit	
Emeka Ebirim	2166	

Subclass	Date 8/24/2006	Examiner
updated	8/24/2006	EE
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	t search (see earch notes)	8/25/2006	EE

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search	8/24/2006	EE
Consulted Pham Khanh (primary)	8/24/2006	EE
Google search	8/24/2006	EE
ACM search	8/24/2006	EE